

2881

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

	DATE	EXMR
UPDATE Search From 09/668, 697 Cite	6/4/04	JLK
(SPIRAL 82 on CIR 83 on ANG 84) <u>WITH</u> (SCAN on MOV 83) <u>SAME</u>		
(C scanning electron microscope on SEM 92 PARTICLE AD; BAW)		
invention Search		